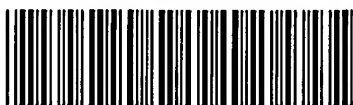


Search Notes

Application/Control No.

10/509,631

Examiner

David Mis

Applicant(s)/Patent under
Reexamination

NAGANO, SEIDO

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner
331	46	12/20/2005	DM
	55		
	172		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
USPGPUB	(see	12/20/2005	DM
	history)		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR